ICP-AES法测定焊锡中多种杂质元素

纪杉 北京 岛津(香港)有限公司分析中心 100020

摘 要: 用电感耦合等离子发射光谱法(ICP -AES)直接同时测定焊锡中多种杂质元素

(P, Fe, As, In, Sb, Au, Pb, Bi, Cu, Al, Ni, Zn, Cd)。在优化仪器的工作条件下, 以基体匹配法配制工作曲线标样, 有效地消除基体干扰。方法简便、可靠并得到满意的分析结果。检出限为00001%~0001%,回收率在956%~105%范围内, 多数分析元素的RSD小于5%。

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Determination of multi-elements in soldering tin by ICP-AES

100020

Abstract: A method was describeb for simultaneous determination of multi-elements in soldering tin by Inductively Coupled Plasma Atomic Emission Spectrometry(ICP-AES)in this paper. The operational parameters were optimized, and the interference from matrix was eliminated with matrix matching. The satisfactory results were obtained with this simple and effective method. The detection limit of analytical elements in the soldering tin sample ranged from 0.00001% to 0.0001%, the recovery was within the range of 95.6% to 105 Key words:

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